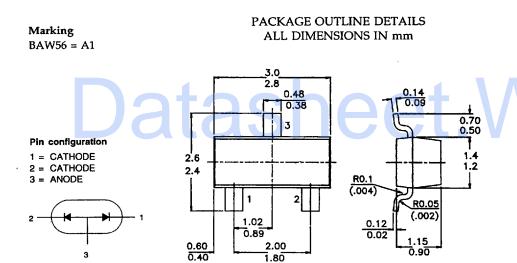


SILICON PLANAR EPITAXIAL HIGH-SPEED DIODES

Silicon planar high-speed switching series diode pair



ABSOLUTE MAXIMUM RATINGS

Continuous reverse voltage

Repetitive peak reverse voltage

Continuous reverse voltage	v_{R}	max.	75 V
Repetitive peak reverse voltage	V_{RRM}	max.	85 V
Repetitive peak forward current	I_{FRM}	max.	450 mA
Junction temperature	$T_{\mathbf{i}}$	max.	150 °C
Forward voltage at IF = 50 mA	$\vec{v_{F}}$	<	1,0 V
Reverse recovery time when switched from			
$I_F = 10 \text{ mA} \text{ to } I_R = 10 \text{ mA}; R_L = 100 \Omega;$			
measured at $I_R = 1 \text{ mA}$	t _{rr}	<	4 ns
Recovery charge when switched from			
$I_F = 10$ mA to $V_R = 5$ V; $R_L = 100 \Omega$	Q_s	<	45 pC
RATINGS (per diode) (at T _A = 25°C unless otherwise spe	ecified)		
Limiting values			

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 $V_{\mathbf{R}}$

75 V

85 V

max.

V_{RRM} max.



Forward current (d.c.) Repetitive peak forward current Non-repetitive peaK forward current (per crystal)	I _F I _{FRM}	max. max.	
t = 1 μs t = 1 ms	I _{FSM}	max.	
t = 1 s	I _{FSM} I _{FSM}	max. max.	
Storage temperature range	T_{stg}	–55 to	+150 °C
Junction temperature	T_{j}	max.	150 ℃
THERMAL RESISTANCE			
From junction to ambient	R _{thj-a}	=	500 K/W
CHARACTERISTICS (per diode) (at $T_A = 25$ °C unless otherwise $T_j = 25$ °C unless otherwise specified Forward voltage	specifie	d)	
$I_F = 1 \text{ mA}$	VF	<	715 mV
$I_F = 10 \text{ mA}$	VF	<	855 mV
$I_F = 50 \text{ mA}$	v_F	<	1000 mV
$I_{\mathbf{F}} = 150 \text{ mA}$	$V_{\mathbf{F}}$	<	1250 mV
Reverse current			
$V_R = 25V; T_j = 150 ^{\circ}C$	$I_{\mathbf{R}}$	<	30 μA
$V_R = 75 \text{ V}$	$I_{\mathbf{R}}$	<	1,0 μΑ
$V_R = 75V; T_j = 150 ^{\circ}C$	$I_{\mathbf{R}}$	<	50 μA
Diode capacitance			
$V_R = 0$; $f = 1$ MHz	C_d	<	2,0 pF
Forward recovery voltage when switched to			
$I_F = 10 \text{mA}; t_r = 20 \text{ns}$	V_{fr}	<	1,75 V